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WASHINGTON, D.C. 2023I
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**CONFIRMATION NO. 3339** 

SERIAL NUMB 09/733,980		FILING DATE 12/12/2000 RULE	(	CLASS 250	GRO	<b>UP AR</b> 2881	T UNIT		ATTORNEY OCKET NO. 862.C2072
APPLICANTS  Masato Muraki, Tokyo, JAPAN; Yoshikiyo Yui, Tochigi, JAPAN;  ** CONTINUING DATA **********************************									
Foreign Priority claimed  35 USC 119 (a-d) conditions  Met after property claimed  Wes no no Met after property claimed  Wes no Met after property claimed  Acknowledged Examiner's Signature Initials				STATE OR COUNTRY JAPAN	SHEETS DRAWING 15		TOTAL CLAIMS 23		INDEPENDENT CLAIMS 7
ADDRESS 05514									
TITLE Charged-particle beam exposure apparatus, charged-particle beam exposure method, control data determination method, and device manufacturing method using this method									
RECEIVED	IVED Noto charge/credit DEPC				DUNT	All Fees  1.16 Fees (Filing)  1.17 Fees (Processing Ext. of time)  1.18 Fees (Issue)  Other  Credit			cessing Ext. of

